

Notice of References CitedApplication/Control No. ²

09/649,128

Applicant(s)/Patent Under
Reexamination
OHTA, SEIYA

Examiner

Nelson D. Hernandez

Art Unit

2612

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,249,317 B1	06-2001	Hashimoto et al.	348/364
	B	US-5,124,842	06-1992	Honda et al.	359/561
	C	US-5,347,371	09-1994	Nishimura et al.	358/453
	D	US-5,751,354	05-1998	Suzuki et al.	348/349
	E	US-6,088,059	07-2000	Mihara et al.	348/335
	F	US-5,337,152	08-1994	Kotaki, Hiroaki	348/234
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Josep Garcia, Juan M. Sanchez, Xavier Orriols and Xavier Binefa."Chromatic aberration and depth extraction"; 3-7 Sept. 2000 pages 762-765 vol. 1 Pattern Recognition, 2000. Proceedings. 15th International Conference
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.